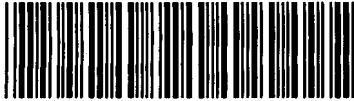


Search Notes

Application/Control No.

10/676,659

Examiner

Hanh Nguyen

Applicant(s)/Patent under
Reexamination

CHAVEZ ET AL.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
370	352	11/1/2007	HN
	401		
	389		
	225		
	216		
	218		
	219		
	242		
370	356		
379	52		
	93.17		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	11/1/2007	HN